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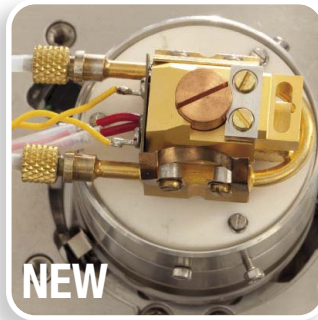
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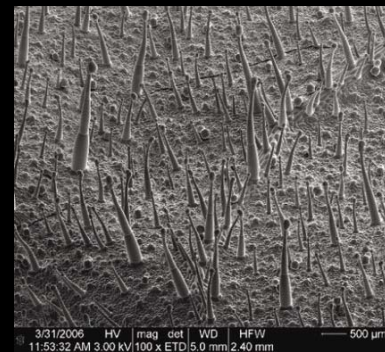
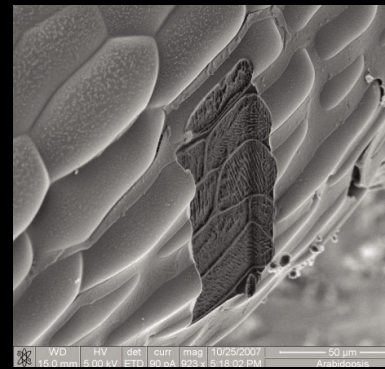
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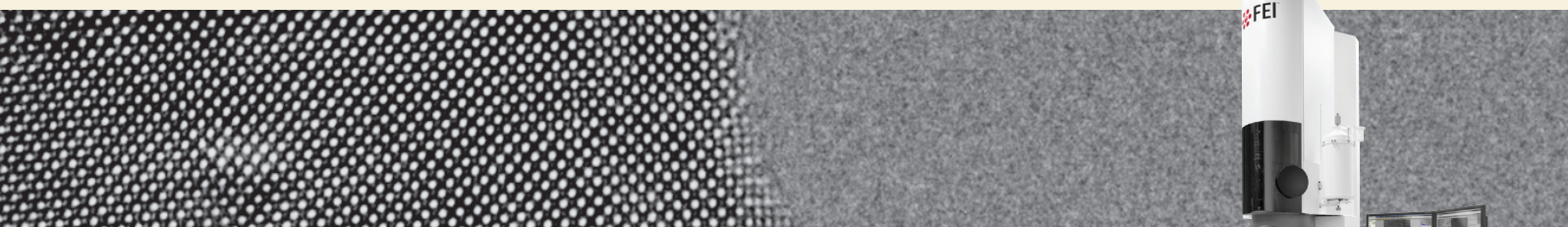
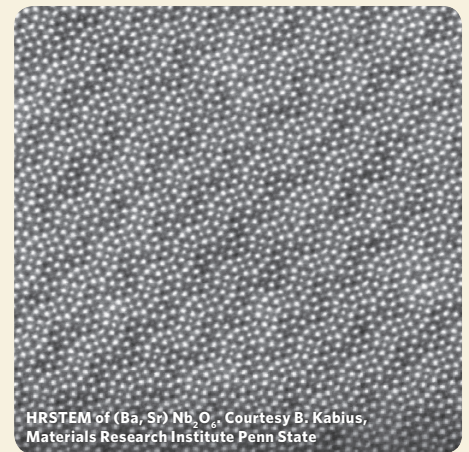
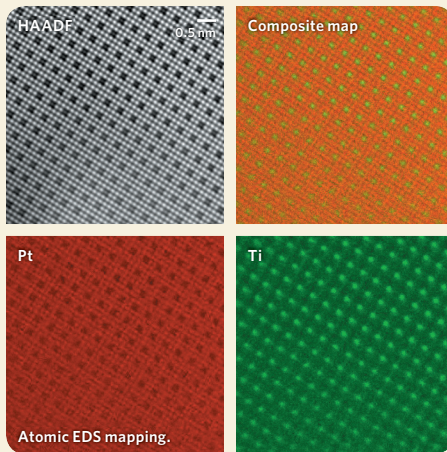
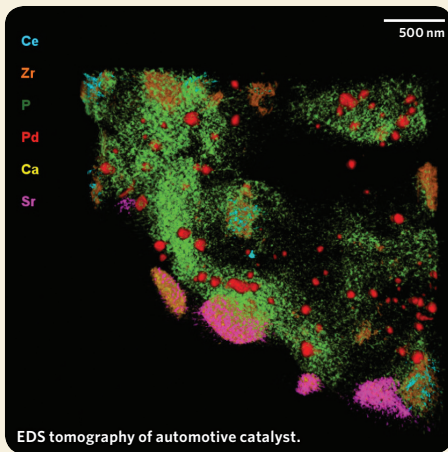
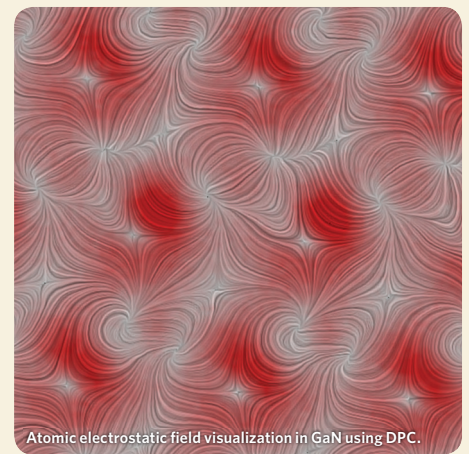
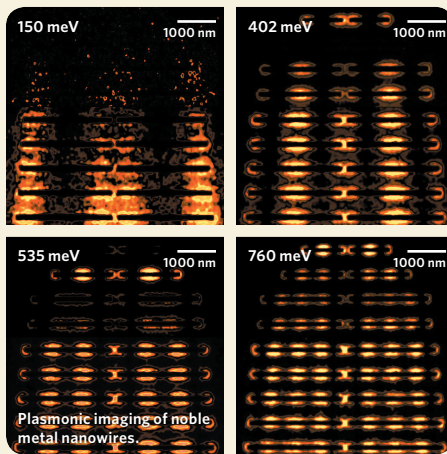
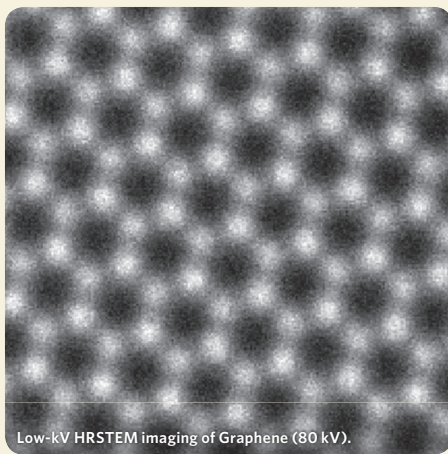
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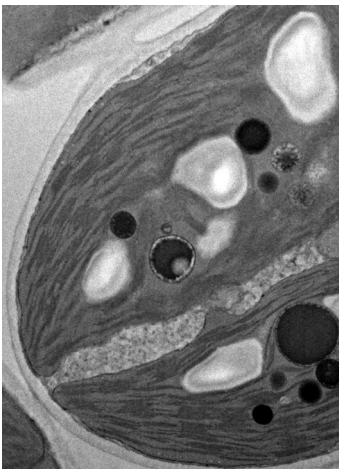
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August 2015

BIOLOGICAL APPLICATIONS AND TECHNIQUES

- Ultrastructural Visualization of Vaccine Adjuvant Uptake *In Vitro* and *In Vivo* 791
Fabiola Giusti, Anja Seubert, Rocco Cantisani, Marco Tortoli, Ugo D'Oro, Ilaria Ferlenghi, Romano Dallai, and Diego Piccioli
- Simultaneous Observation of Cells and Nuclear Tracks from the Boron Neutron Capture Reaction by UV-C Sensitization of Polycarbonate 796
Agustina Portu, Andrés Eugenio Rossini, Silvia Inés Thorp, Paula Curotto, Emiliano César Cayetano Pozzi, Pablo Granell, Federico Golmar, Rómulo Luis Cabrini, and Gisela Saint Martin
- Bone Diagenesis and its Implication for Disease Diagnosis: The Relevance of Bone Microstructure Analysis for the Study of Past Human Remains 805
Sandra Assis, Anne Keenleyside, Ana Luísa Santos, and Francisca Alves Cardoso
- Characterization of the Distance Relationship Between Localized Serotonin Receptors and Glia Cells on Fluorescence Microscopy Images of Brain Tissue 826
Jaroslav Jacak, Susanne Schaller, Daniela Borgmann, and Stephan M. Winkler
- Tracing CD34+ Stromal Fibroblasts in Palatal Mucosa and Periodontal Granulation Tissue as a Possible Cell Reservoir for Periodontal Regeneration 837
Alexandra Roman, Emöke Páll, Carmen M. Mihu, Adrian S. Petruțiu, Lucian Barbu-Tudoran, Radu S. Câmpian, Adrian Florea, and Carmen Georgiu
- Bond Strength of High-Viscosity Glass Ionomer Cements is Affected by Tubular Density and Location in Dentin? 849
Tamara K. Tedesco, Ana Flávia B. Calvo, Gabrielle G. Domingues, Fausto M. Mendes, and Daniela P. Raggio
- Phase and Texture Characterizations of Scar Collagen Second-Harmonic Generation Images Varied with Scar Duration 855
Guannan Chen, Yao Liu, Xiaoqin Zhu, Zufang Huang, Jianyong Cai, Rong Chen, Shuyuan Xiong, and Haishan Zeng
- Automatic Evaluation of Collagen Fiber Directions from Polarized Light Microscopy Images 863
Kamil Novak, Stanislav Polzer, Michal Tichy, and Jiri Bursa
- A Refined Single-Particle Reconstruction Procedure to Process Two-Dimensional Crystal Images from Transmission Electron Microscopy 876
Qie Kuang, Pasi Purhonen, Thirupathi Pattipaka, Yohannes H. Ayele, Hans Hebert, and Philip J.B. Koec
- Reliable Detection and Smart Deletion of Malassez Counting Chamber Grid in Microscopic White Light Images for Microbiological Applications 886
Emmanuel Denimal, Ambroise Marin, Stéphane Guyot, Ludovic Journaux, and Paul Molin
- Cryostat Slice Irregularities May Introduce Bias in Tissue Thickness Estimation: Relevance for Cell Counting Methods 893
Anna Puigdemívol-Sánchez, Albert Giralt, Anna Casanovas, Jordi Alberch, and Alberto Prats-Galino
- A Method for Preparing Difficult Plant Tissues for Light and Electron Microscopy 902
Peta L. Clode



On the Cover: New technique for TEM preparation of difficult plant materials. For further information please see Clode pp 902–909.

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MATERIALS APPLICATIONS AND TECHNIQUES

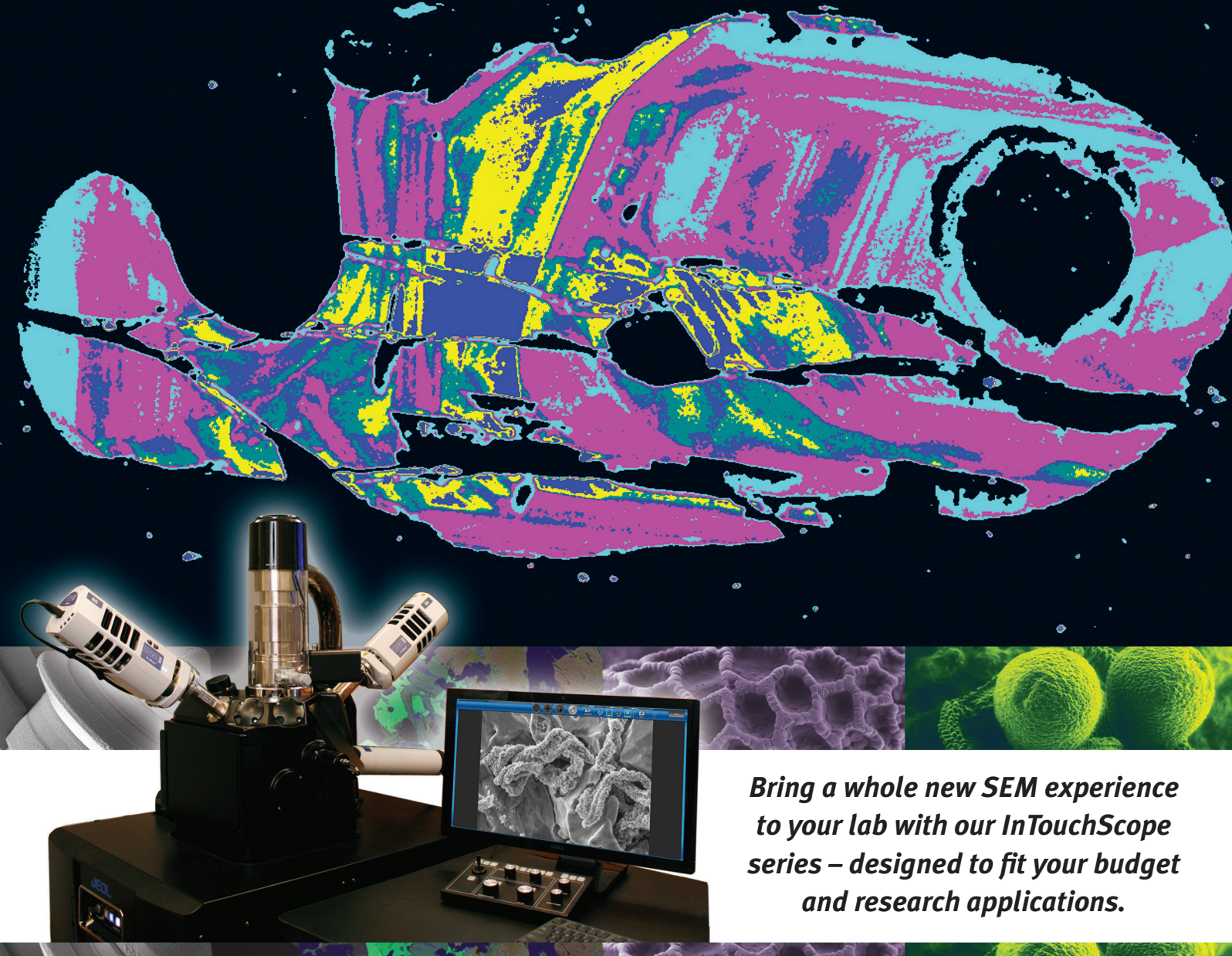
- Voltage and Dopant Concentration Measurements of Semiconductors using a Band-Pass Toroidal Energy Analyzer Inside a Scanning Electron Microscope 910
Avinash Srinivasan and Anjam Khursheed
- Electron Backscatter Diffraction and Transmission Kikuchi Diffraction Analysis of an Austenitic Stainless Steel Subjected to Surface Mechanical Attrition Treatment and Plasma Nitriding 919
Gwénaëlle Proust, Delphine Reira, Mahdi Chemkhi, Arjen Roos, and Clemence Demangel
- Characterization of Sputtered CdTe Thin Films with Electron Backscatter Diffraction and Correlation with Device Performance 927
Matthew M. Nowell, Michael A. Scarpulla, Naba R. Paudel, Kristopher A. Wieland, Alvin D. Compaan, and Xiangxin Liu
- The Internal Structure of Macroporous Membranes and Transport of Surface-Modified Nanoparticles 936
Sang J. Lee, Kiwoong Kim, and Sungsook Ahn
- Accurate Nanoscale Crystallography in Real-Space Using Scanning Transmission Electron Microscopy 946
J. Houston Dycus, Joshua S. Harris, Xiahan Sang, Chris M. Fancher, Scott D. Findlay, Adedapo A. Oni, Tsung-ta E. Chan, Carl C. Koch, Jacob L. Jones, Leslie J. Allen, Douglas L. Irving, and James M. LeBeau
- Solid State Reaction Mechanism and Microstructure Evolution of Ni-Al Powders during High Energy Ball Milling Revisited by TEM 953
Guohua Fan, Lin Geng, Yicheng Feng, Xiping Cui, and Xudong Yan
- Characterization of Darai Limestone Composition and Porosity Using Data-Constrained Modeling and Comparison with Xenon K-Edge Subtraction Imaging 961
Sheridan C. Mayo, Sam Y.S. Yang, Marina Pervukhina, Michael B. Clennell, Lionel Esteban, Sarah C. Irvine, Karen K. Siu, Anton S. Maksimenko, and Andrew M. Tulloh
- Evaluating Deformation-Induced Grain Orientation Change in a Polycrystal During *In Situ* Tensile Deformation using EBSD 969
Thomas E. Buchheit, Jay D. Carroll, Blythe G. Clark, and Brad L. Boyce
- EBSDinterp 1.0: A MATLAB® Program to Perform Microstructurally Constrained Interpolation of EBSD Data 985
Mark A. Pearce
- Quantitative Chemical Mapping of InGaN Quantum Wells from Calibrated High-Angle Annular Dark Field Micrographs 994
Daniel Carvalho, Francisco M. Morales, Teresa Ben, Rafael García, Andrés Redondo-Cubero, Eduardo Alves, Katharina Lorenz, Paul R. Edwards, Kevin P. O'Donnell, and Christian Wetzel
- iSpectra: An Open Source Toolbox For The Analysis of Spectral Images Recorded on Scanning Electron Microscopes 1006
Christian Liebske
- Multiplexed TEM Specimen Preparation and Analysis of Plasmonic Nanoparticles 1017
Sean K. Mulligan, Jeffrey A. Speir, Ivan Razinkov, Anchi Cheng, John Crum, Tilak Jain, Erika Duggan, Er Liu, John P. Nolan, Bridget Carragher, and Clinton S. Potter
- Electron Correlation Microscopy: A New Technique for Studying Local Atom Dynamics Applied to a Supercooled Liquid 1026
Li He, Pei Zhang, Matthew F. Besser, Matthew Joseph Kramer, and Paul M. Voyles
- Theory and New Applications of *Ex Situ* Lift Out 1034
Lucille A. Giannuzzi, Zhiyang Yu, Denise Yin, Martin P. Harmer, Qiang Xu, Noel S. Smith, Lisa Chan, Jon Hiller, Dustin Hess, and Trevor Clark

BOOK REVIEWS

- Practical Materials Characterization 1049
Fumiya Watanabe
- Optical Nanoscopy and Novel Microscopy Techniques 1050
Guy Cox

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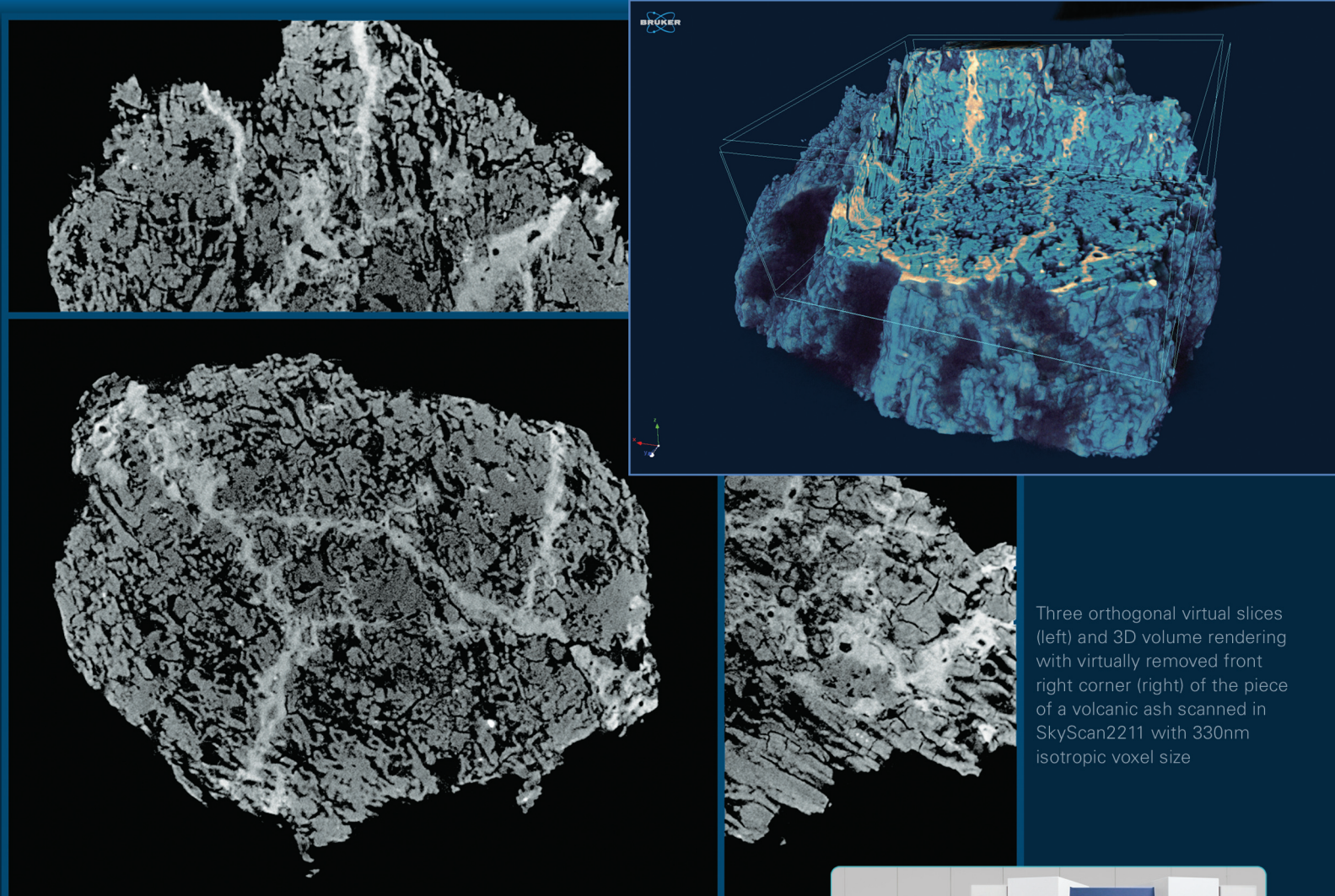


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Three orthogonal virtual slices (left) and 3D volume rendering with virtually removed front right corner (right) of the piece of a volcanic ash scanned in SkyScan2211 with 330nm isotropic voxel size

NEW

SKYSCAN 2211 MULTISCALE X-RAY NANOTOMOGRAPH



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The new MULTISCALE X-ray nanotomograph SkyScan 2211 covers the widest range of object sizes and spatial resolutions in one single instrument. It opens unique possibilities for 3D imaging and exact modelling of geological materials, biomaterials, composites, implants, etc

- Up to 8Kx8K pixels in every virtual slice, up to 2300 such slices can be reconstructed after a single scan,
- Object size up to 204mm in diameter, submicron resolution for small samples, 100nm nominal resolution,
- 20-190kV X-ray source, flat-panel sensor and cooled CCD camera to cover wide range of magnifications,
- World's fastest hierarchical 3D reconstruction (InstaRecon®) with 20x...100x speed-up,
- Software for 2D/3D image analysis, task lists, user plug-ins, surface and volume rendering,
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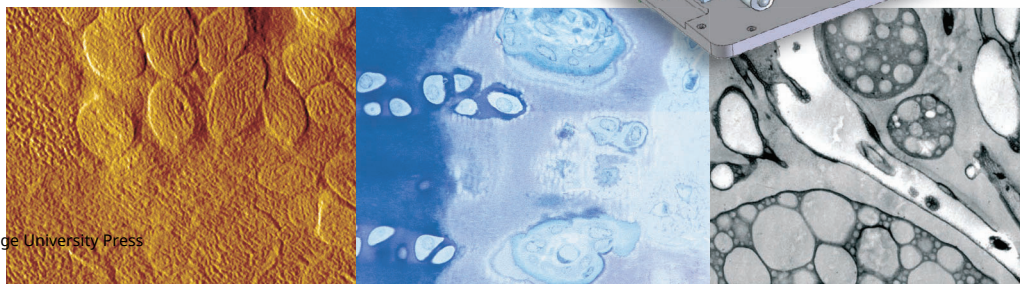
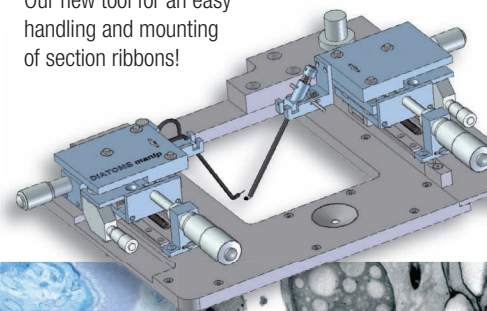
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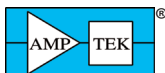
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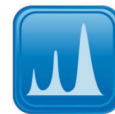
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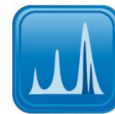
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